

Hi5

A New High Performance UHV SIMS Tool with Simultaneous Positive and Negative SIMS Detection and Plasma FIB

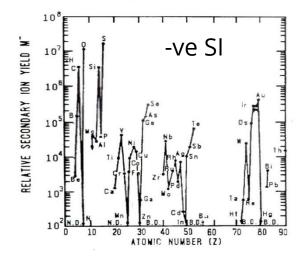


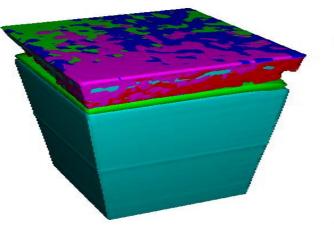
Why collect positive and negative ions simultaneously?

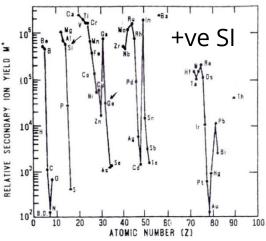
Often need to gather complimentary data with +ve and -ve secondary ions from an inhomogeneous sample (only one shot!)

Changing the extraction polarity will shift the primary ion beam and make registration difficult or impossible

Changing extraction polarity takes time







Taken from: SIMS Handbook ed: Wilson R.G.; Stevie, F.A.; Magee, C.W.; John Wiley & Sons Inc. NY 1989



Hi5 Focused Ion Beam SIMS

- Collect positive and negative secondary ions simultaneously with accurate registration of images / depth profiles
 - Two quadrupole analysers with low field (~10V/mm) extraction field) in optimum geometry
- Oxygen / inert gas primary beam (FIB) and Cs primary beam
 - Plasma FIB ion gun Oregon Physics Hyperion II (normal incidence)
 - Hiden IG5C Cs ion gun 45 degrees
- 5 axis high precision stage with sample heating / cooling and external electrical connections to operate devices during analysis.
- UHV vacuum performance (as interested in atmospheric species)
- Vibration isolated bed for 20nm resolution
- Ability to have high mass resolution to separate D₂ and He as Deuterium and oxygen-18 diffusion studies for fuel cell and metallurgy investigations.



Hiden FIB - SIMS

EQS – On-axis sampling, energy resolving mass spectrometer

- ➤ On-axis collection for optimum alignment
- > Low extraction field
- > Can be fitted with DLS-20 HMR spectrometer
- > Efficient 45° sector permits high abundance sensitivity (1E6) and filters out electrons in negative ion mode



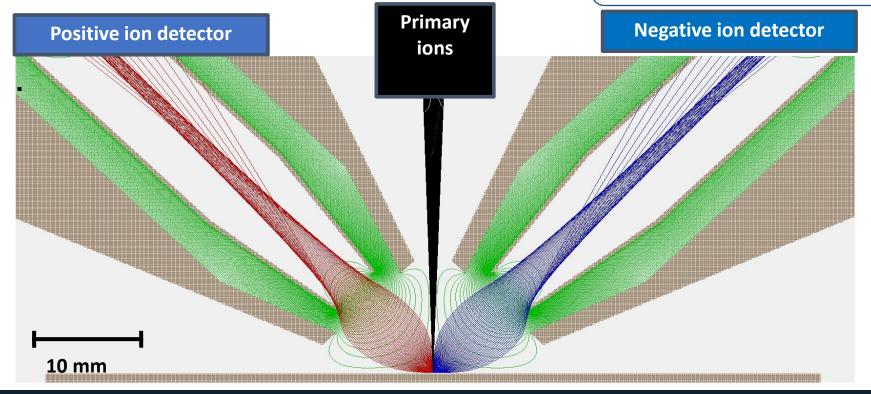




Hi5 Simultaneous Dual Polarity Detection FIB

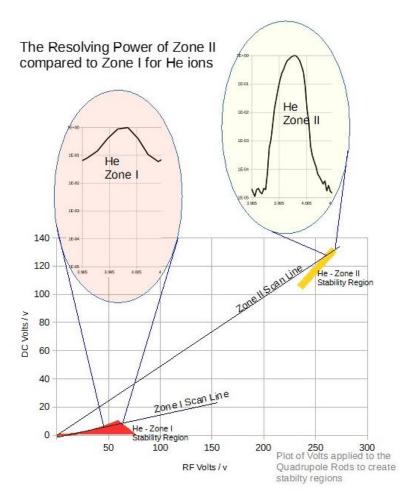
- > SIMION ray-tracing model of a configuration for Simultaneous Positive Negative secondary ion detection with two Hiden SIMS detectors
- > Opposing balanced symmetrical fields enhance high collection efficiency
- ➤ Low extraction field (10V/mm) reduced primary beam aberrations
- > Sputtering by a normally incident primary beam.

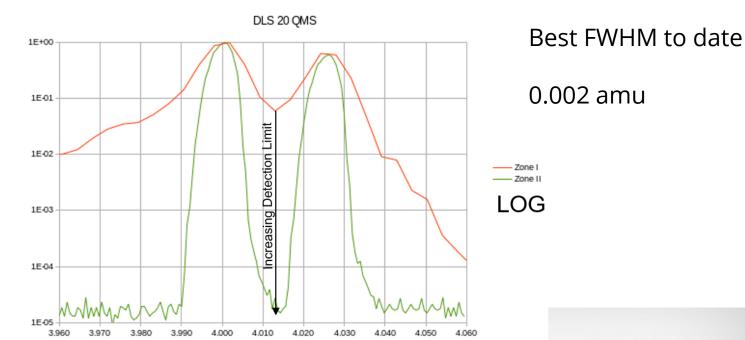
Positive Ions Negative Ions Primary Ions Equipotentials





DLS-20 Mass Filter – 20mm pole diameter Operates in both first and second stability region







20 mm HMR quadrupole SIMS analyser

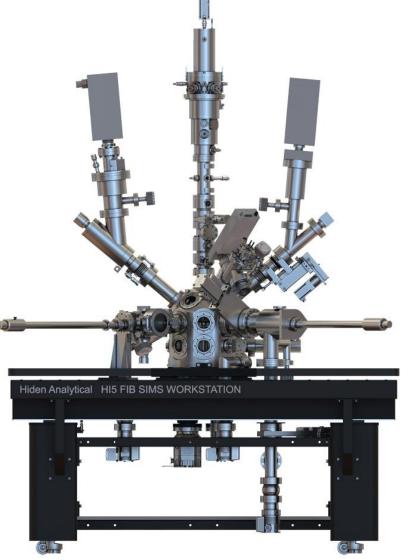
Charge compensation electron gun

Loadlock 1

UHV high stability chamber

5 axis stage

Hi5_SIMS Instrument



9 mm quadrupole **SIMS** analyser

Secondary Electron detector

IG5C caesium ion gun

Loadlock 2 and process chamber

Anti-vibration table

Oregon Physics Hyperion II plasma FIB



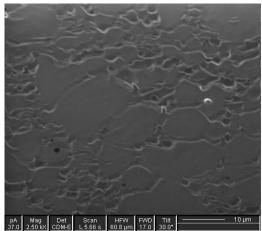


FIB-SIMS

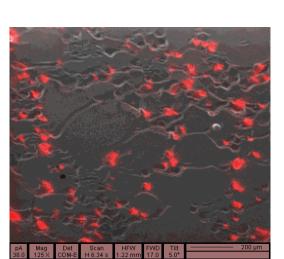
 $Li_{6.55}Al_{0.15}-0.3La_3Zr_2O_{12}$



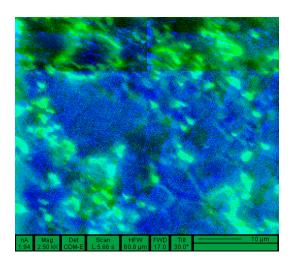
Al+ mapping region 3, cleaned area 20 nA 5 min, 1.94 nA current; 200 nm resolved area



Al+ in red; overlay (below)



LaO+ in blue; Li+ green overlay



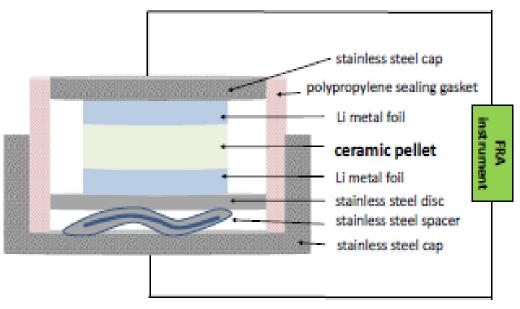
Non-homogeneous AL-distribution along the grain boundaries Two distinct areas that are Li-rich:

- 1) Associated to Al enrichment
- 2) Associated to Al and La depletion

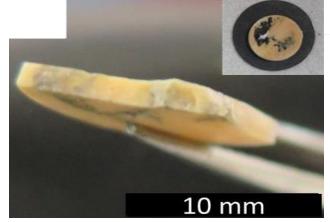


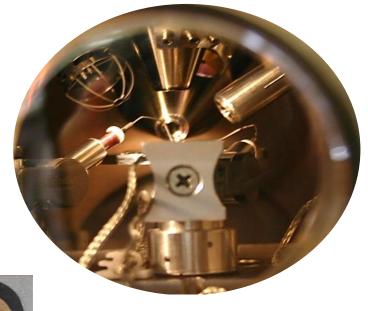
Imperial College work with Dual Polarity Detection

Dendrite formation in solid electrolyte garnets Li_{6.55}Al_{0.15}-_{0.3}La₃Zr₂O₁₂









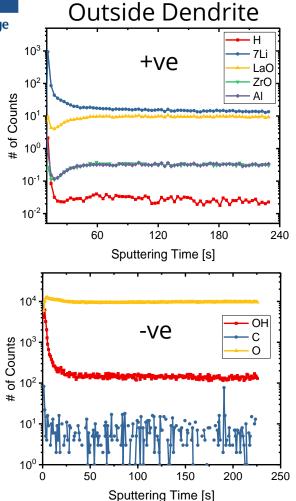


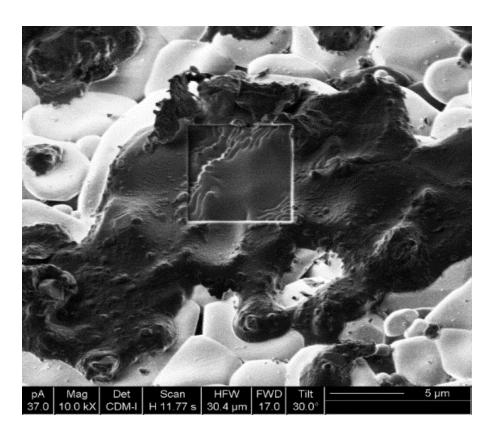


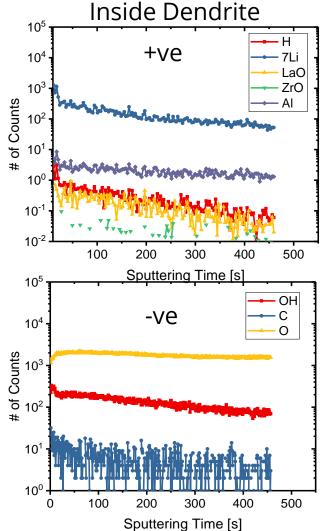
ELECTROCERAMIC MATERIALS

Imperial College London

Simultaneous Dual Polarity Secondary ion Detection









Summary

- Hiden Hi5 first commercial simultaneous collection of positive and negative secondary ions
- Integration of plasma FIB using oxygen or xenon for highest sensitivity
- Five axis stage for accurate sample positioning
- UHV performance
- Multiple additional features such as heating and cooling, micro-manipulation and process chambers allow in-situ processing and analysis without leaving vacuum
- Delivered to Imperial College department of Materials



